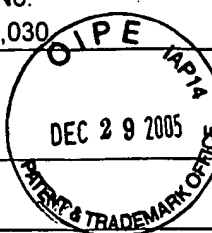


**AMENDED**

Page 1 of 2

<b>Form PTO-1449</b> (modified)  List of Patents and Publications for Applicant's  <b>INFORMATION DISCLOSURE STATEMENT</b>  (Use several sheets if necessary)	Atty. Docket No. METR:002	Serial No. 10/669,030	
	Applicant Dale A. Harrison		
	Filing Date: September 23, 2003	Group: 2878	
U.S. Patent Documents See Page	Foreign Patent Documents See Page	Other Art See Pages 1-2	

U.S. Patent Documents							
Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A1						

Foreign Patent Documents							
Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
CH	C1	McPherson Product Brochure "Reflectometer for Sample Analysis," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
CH	C1A	McPherson Product Brochure "Spectral Reflectometer," McPherson, Inc., Massachusetts, November 12, 2001, 1 pg.
CH	C2	McPherson Product Brochure "VUVaS Spectrophotometers for 115 nm to >380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-4 pps.
CH	C3	McPherson Product Brochure "VUVaS Spectrophotometers, Made to Measure 115-380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-8 pps.
CH	C4	Action Research Product Brochure "Action Research Purged CAMS Optical Measurement System," Action Research Corporation, Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
CH	C5	"The Thin Film tool for next generation lithography at 157nm," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet On February 19, 2002, 1pg.
CH	C6	"SE and GXR combined on the same instrument," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet on February 19, 2002, 1pg.
CH	C7	"The ideal Thin Film characterization unit for Development and Pilot Line environment," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet on February 19, 2002, 1 pg.

Examiner: **CONSTANTINE HANNAHER** Date Considered: **JAN 10 2006**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>Form PTO-1449</b> (modified)		Atty. Docket No. METR:002	Serial No. 10/669,030
List of Patents and Publications for Applicant's  <b>INFORMATION DISCLOSURE STATEMENT</b>  (Use several sheets if necessary)		Applicant Dale A. Harrison	
		Filing Date: September 23, 2003	Group: 2878
U.S. Patent Documents See Page	Foreign Patent Documents See Page	Other Art See Pages 1-2	

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
CH	C8	"VUV-VASE™, The Award Winning VUV-VASE™ is the latest addition to our line of Spectroscopic Ellipsometers," Web pages from <a href="http://www.jawoolam.com">http://www.jawoolam.com</a> , J.A. Woollam Company, Nebraska, Printed From Internet on November 5, 2002, 1-2 pps.
CH	C9	"Vacuum UV Spectroscopic Ellipsometers," Web pages from <a href="http://www.sentech.de">http://www.sentech.de</a> , Sentech Instruments, Printed From Internet on February 20, 2002, 1-3 pps.

Examiner: **CONSTANTINE HANNAHER** Date Considered: **JAN 10 2006**

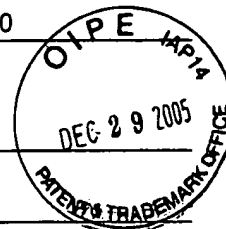
EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**Form PTO-1449** (modified)

List of Patents and Publications for Applicant's

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Atty. Docket No.  
METR:002Serial No.  
10/669,030Applicant  
Dale A. HarrisonFiling Date:  
September 23, 2003Group:  
2878U.S. Patent Documents  
See Page 1Foreign Patent Documents  
N/AOther Art  
See Page 1**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
CH	A31	US2002/0030826 A1	3/14/02	Chalmers et al.	—	—	7/3/01
CH	A32	4,368,983 A	1/18/83	Bennett	—	—	11/13/80

**Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

**Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
CH	C11	Rubloff, "Surface Reflectance Spectroscopy System", Technical Disclosure, Ip.com, <a href="http://www.ip.com">www.ip.com</a> , May 1, 1977, 5 pgs. TDB 05-77 p4811-4813

Examiner: **CONSTANTINE HANNAHER** Date Considered: **JAN 10 2006**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.